Inspection Tool Supplier Challenges

- EUV Reticle Pattern Inspection General Concerns
  - Technical
    - System: Market requirements → resolution, S/N, data rate,…
    - HW subsystems: Illumination source, sensor, optics, …
    - Production worthiness: MTBF, MTTR, …
  - Financial
    - NRE, market size, ASP, ROI, consumable costs,…

- EUV Reticle Pattern Inspection Specific Concerns
  - Is actinic inspection required?
  - Will non-actinic inspection be a reasonable alternative?
  - Are there new printable defect types?
Recommendations

- Perform Appropriate Inspections at Appropriate Process Steps
  - Substrate
  - MLS / Absorber
  - Patterned Absorber

- Utilize Current Optical Pattern Inspection Infrastructure to Drive EUV Reticle Yield Learning
  - Optimize optical contrast
  - Leverage installed equipment base